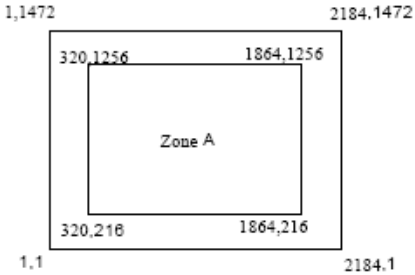
DEFECT DEFINITIONS

OPERATING CONDITIONS

All defect tests performed at T=25oC

SPECIFICATIONS

Classification	Point Defect		Cluster Defect		Column Defect	
	Total	Zone A	Total	Zone A	Total	Zone A
C1	≤5	≤2	0	0	0	0
C2	≤10	≤5	≤4	≤2	0	0



Zone A = Central 1544H x 1040V Region

Point Defects Dark: A pixel that deviates by more than 6% from neighboring pixels when illuminated to 70% of saturation

-- OR --

Bright: A pixel with a dark current greater than 15000e/pixel/sec at 25C.

Cluster Defect A grouping of not more than 5 adjacent point defects

Column Defect A grouping of >5 contiguous point defects along a single column

A column containing a pixel with dark current > 12,000e/pixel/sec (bright column)

--OR—

A column that does not meet the minimum vertical CCD charge capacity (low charge capacity column)

--OR—

A column which loses more than 250 e under 2Ke illumination (trap defect)

Neighboring Pixels The surrounding 128 x 128 pixels or ± 64 column/rows

Defect Separation Column and cluster defects are separated by no less than two (2) pixels in any direction (excluding single pixel defects)